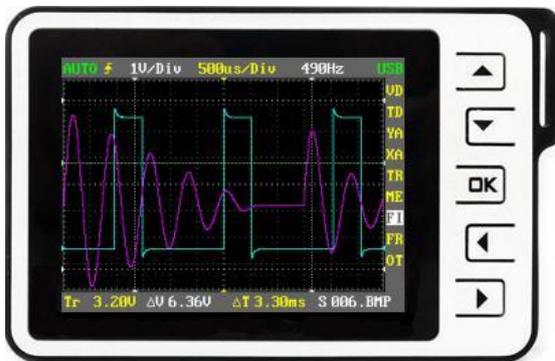
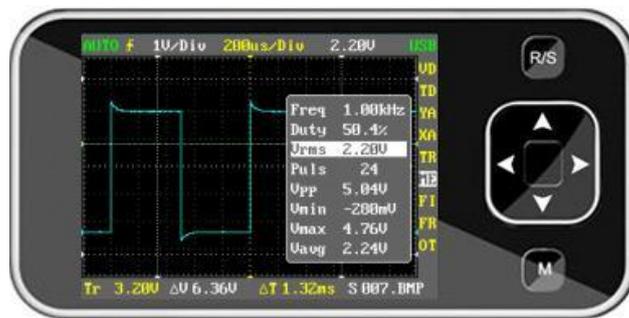


BenF V3 firmware users guide

DSO Nano V1



DSO Nano V2

Introduction

The BenF V3 firmware has been developed to overcome some of the limitations and issues with the official firmware releases. In particular this applies to improved SD card support, a more advanced no loss sampling algorithm and a more intuitive user interface. The firmware is designed to run on Seeed Studio DSO Nano V1 and V2 hardware. It may or may not work with hardware supplied by other manufacturers.

The firmware is free of charge to individuals in its binary format and is put into the public domain in the hope that it will be useful for others and not only the author. Any use of this firmware is at your own risk. No express or implied warranty is granted for the firmware or related documentation and under no circumstance can the author be held responsible for any direct or consequential damage that may arise from using it.



Background

The DSO Nano first appeared in the market fall 2009 with a compact attractive design and a very competitive price. Despite its limited bandwidth, the Nano is nonetheless an excellent tool for a range of practical measuring tasks such as basic electronics design/repair and auto/marine diagnostics. The stock firmware however is very basic and despite a few updates along the way, much is still left to be desired. Even with the most recent official 2.5e release, we're not much further than a pretty enclosure with potential. To realize this potential, a complete rewrite of the firmware was needed.

A key feature of any digital oscilloscope is its data acquisition capability and to get this right we need a three phase approach to sampling. That is pre-fetch, trigger-fetch and post-fetch. An acquisition must run uninterrupted until a trigger is found (forever if need be) while the sampling buffer is continually reused in a round-robin fashion. No samples must be lost or disregarded during the entire acquisition cycle. When a trigger is found, its position in the

buffer is marked and acquisition continues until the entire sampling buffer is filled with data. The data from this acquisition cycle is then displayed with the trigger point centered on the screen.

The official DSO Nano firmware is using the simplistic single phase acquisition model. That is start acquisition, stop acquisition and then search for a trigger. An issue with this approach is that the trigger (the data of interest) may arrive while we're not acquiring data and so will be lost. This makes it more or less unfit for digital analysis (e.g. SPI, I2C, RS-232, RS-485) and also of limited use for signals like electronic ignition (narrow, infrequent pulses) and many (if not most) other real life measuring and fault finding challenges.

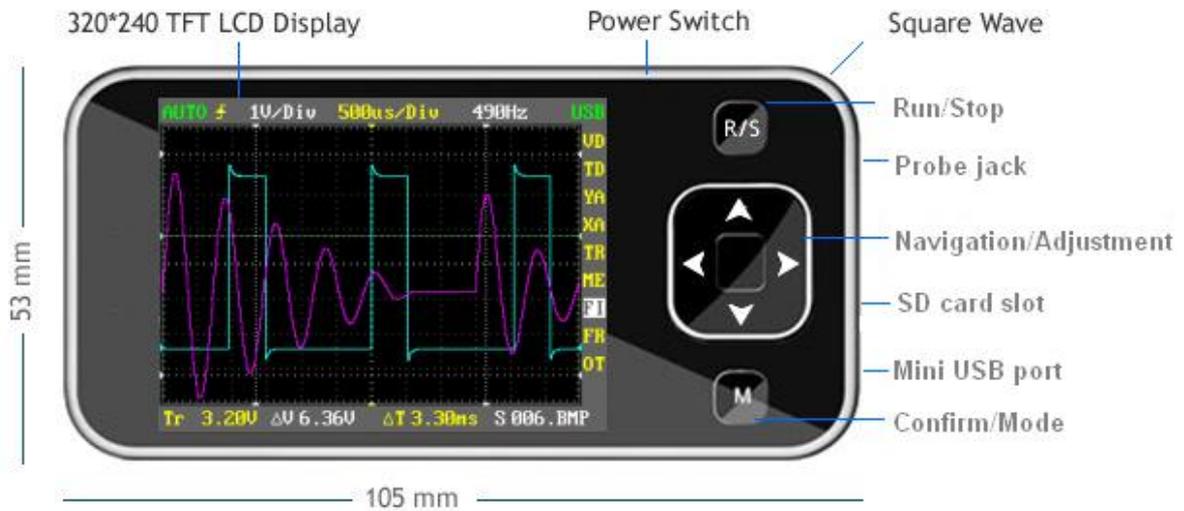
Feature Summary

Thanks to Seeed Studio and its DSO forum, sufficient information has been provided to allow the stock firmware to be replaced with a custom version. Based in part on the official 2.5e source release, V3 has been developed as a complete new firmware replacement. Fixes and new features include the following:

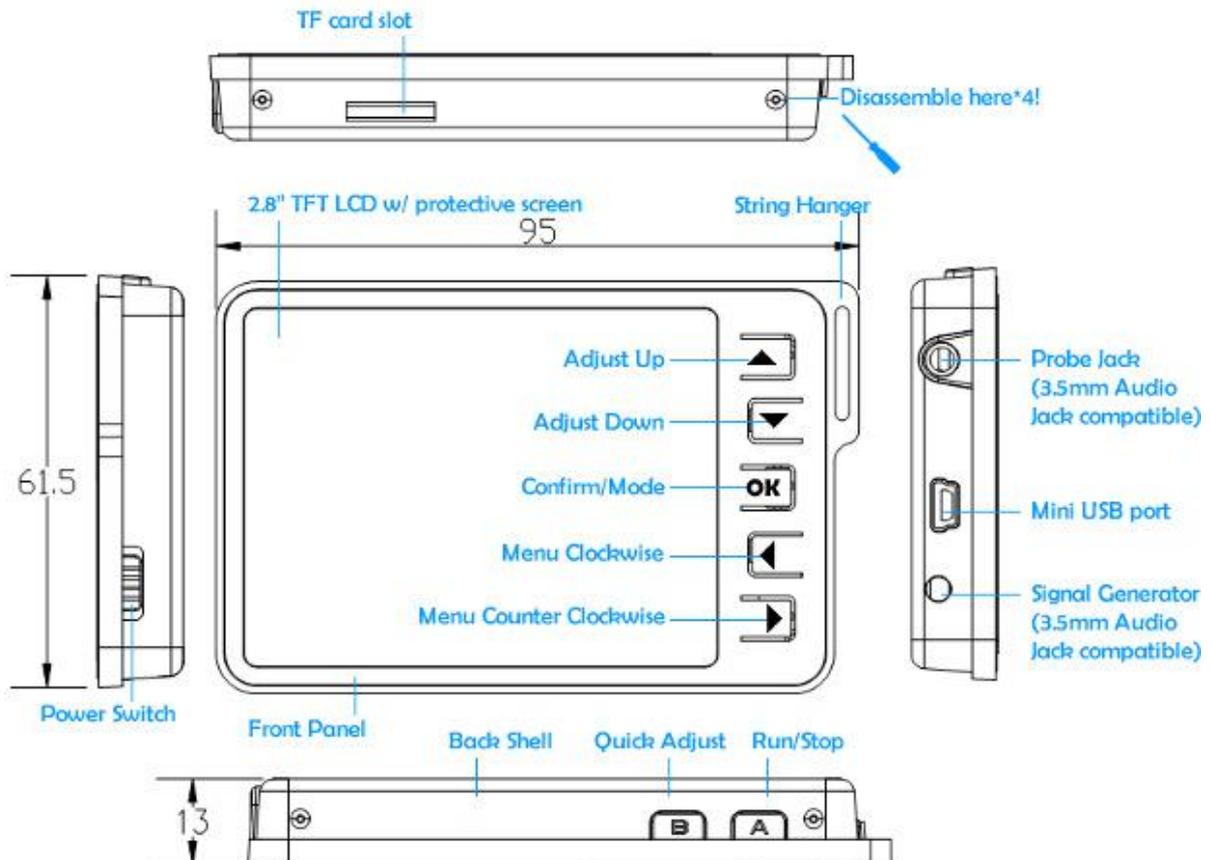
- ✓ Three phase sampling (pre-fetch, trigger-fetch, post-fetch) guaranteed never to miss infrequent events
- ✓ More efficient screen update (10-100 times faster than version 2.5e)
- ✓ Eliminate all flickering and stuck pixels
- ✓ Code is re-written to allow full compile time optimization (much faster, compact and more responsive code)
- ✓ A number of overflow bugs have been fixed (calculations for large time/div settings)
- ✓ Scan has been replaced with a proper continuous real-time scan mode
- ✓ Configuration profiles can be saved to and restored from SD card or flash memory (default power on settings).
- ✓ Waveforms can be saved to and restored from SD cards
- ✓ Screen capture can be saved to bitmap files on SD cards
- ✓ Snapshots of the full DSO sampling buffer can be exported to XML formatted files for further processing and analysis
- ✓ XML formatted files can be imported to both the primary channel and the reference channel
- ✓ Use oversampling and averaging to detect high frequency components on lower frequency waveforms
- ✓ Choice of average and peak acquisition modes
- ✓ A number of issues with incorrect SD card support and file handling in 2.5e have been fixed
- ✓ Files and directories will be created by the DSO Nano as needed without having to preload template files
- ✓ Automatic waveform tuning (FIT mode) can be selected with a dedicated key combination
- ✓ The full sampling buffer can be panned left right on the Nano display
- ✓ Control sampling buffer usage for pre or post trigger priority or fast sampling rate
- ✓ Waveform resizing and vertical scroll capability (zoom in on area of interest)
- ✓ A more relevant collection of information fields is selected for on screen display
- ✓ A more relevant selection of measurements
- ✓ Simultaneous view of all measurements
- ✓ Use common abbreviations and terminology
- ✓ A completely redesigned user interface (no annoying blinking or color abuse)
- ✓ Automatic ground level calibration and manual gain calibration for all input ranges
- ✓ User selectable grid light intensity level
- ✓ Fine tuning of output frequency to three digits
- ✓ Set duty cycle (PWM) of output frequency from fully-off to fully-on in 1% increments
- ✓ Single button quick select for frequently used functions

DSO Nano Operation

The following shows the DSO Nano V1. Note the location of keys (buttons) as they are referred to frequently throughout this document.



DSO Nano V2 has a different layout and one additional quick adjust key (B).



V3 firmware is designed to fully support both V1 and V2 hardware. The same feature set is available on both models and operation is identical except for the differences in layout and the additional quick select key found on V2 hardware. Key to function mapping for the two DSO Nano models is as outlined in the following table:

V1	V2	Function
M	OK	These keys have dual functions. Push and release to open/close popup menus. Push and hold to activate or quick select.
	B	Activate or quick select. This key is identical in function to a push and hold of M or OK.
R/S	A	Start or stop data acquisition.
Arrow keys	Arrow keys	Navigate in menus, move markers and select options.

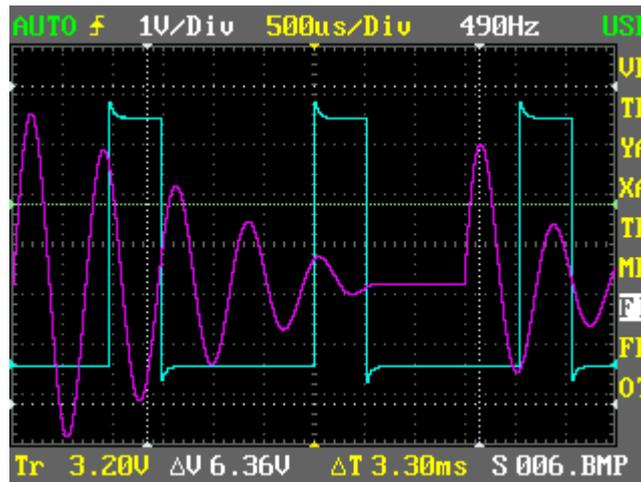
The B key is only available on V2 hardware. DSO Nano V1 users should push and hold the M key to activate functions mapped to this key. V2 users have the option to either press the B key or push and hold the OK key. In the remainder of this document, any reference to the B key can be substituted with a push and hold of the M (V1) or OK (V2) keys.

User Interface

All menu items are available from the right hand side of the display. These are organized in the following main groups:

Main group	Available options
VD Voltage/Div	Select voltage (y-axis) scale
TD Time/Div	Select time (x-axis) scale
YA Y-axis	Set horizontal cursors, ground position, vertical offset and vertical reference offset
XA X-Axis	Set vertical cursors and trigger position
TR Trigger options	Choose trigger mode, level, sensitivity and kind
ME Measurements	Select or display measurements
FI File options	Options for reading and writing from/to SD cards and Flash memory, show/hide reference
FR Frequency	Select output frequency and duty cycle (PWM)
OT Other	Set buffer priority, sampling speed, acquisition mode, probe attenuation, options for calibration and grid intensity level

The following image is an example screen capture showing how the above menu categories appear on the DSO display.



The cyan square wave is a trace of the live input signal and the magenta waveform is a static reference waveform.

Information fields on the top and bottom bars include the following:

Field	Information
AUTO	Trigger Mode NORM, AUTO, SING, SCAN or FIT (red when paused)
f	Trigger Kind Edge rising or edge falling (red if loss of trigger)
1V/Div	Voltage Div Y-axis scaling (red if over/under voltage detected)
500us/Div	Time Div X-axis scaling
490Hz	Measure Measure value
USB	Power USB or battery level indicator
Tr 3.20V	Trigger Level Active trigger level
ΔV 6.36V	Delta V1/V2 Voltage between horizontal cursors V1 and V2
ΔT 3.30ms	Delta T1/T2 Time between vertical cursors T1 and T2
S 006.BMP	Info field Context sensitive information field

Use arrow up/down keys to move between menu groups. Moving past upper/lower wraps around to the opposite side. Within each group there are one or several sub-commands. As an example YA (Y-axis) have sub commands for V1 Cursor, V2 Cursor, Gnd Pos, Vert Pos and Ref Pos. Use the M/OK key to display a popup window with supported sub-commands, up-down to change selection and M/OK to close the popup.

Use left/right keys to change the setting of the selected sub command within the active main group. Use the B key to show/hide cursors, save/load files or reset to a default value.

When input voltage exceeds the range (too high or too low) for the active V/Div, the V/Div information field will display with a red color.

Trigger modes

In NORM trigger mode, the Nano will continuously search for a trigger and not update the display unless a trigger is found. In AUTO mode, the Nano will search for a trigger as for NORM, but force a trigger after 100ms if none was found. SING works as NORM, but will

not initiate a new acquisition cycle after a successful trigger. Use the A key (R/S on V1) to start a new SING cycle.

Choose “Tr. Mode” (Trigger Mode) and press B to activate (or deactivate) FIT mode. In FIT trigger mode, the Nano will automatically identify the type of waveform and adjust the settings to produce a usable display of the input signal. This is similar in function to the Auto push button found on most scopes. The function will track the input signal and continuously adjust trigger level, ground level, V/Div and T/Div in small steps until a stable waveform can be displayed. Manually adjusting trigger level, V/Div or T/Div when in FIT trigger mode will revert to AUTO mode. A stable repeating input signal must be present for this function to work well.

Choose AUTO trigger mode and T/Div greater or equal to 100ms to activate real-time scan. In SCAN mode, data acquisition runs continuously and the input signal is progressively displayed from left to right in real-time disregarding other trigger options. This mode is useful for observing or trending a slow changing signal such as temperature variations or battery charge level.

No trigger found is indicated with the trigger kind (rising/falling) symbol displayed in the color red.

When acquisitions are stopped, trigger mode is displayed with the color red.

Use menu option “Tr.Kind” (Trigger Kind) to select rising or falling edge trigger, “Tr. Level” to set trigger level and “Tr. Sens” to set trigger sensitivity.

Panning the full sampling buffer

Panning left/right is possible through menu item XA (X axis) and sub option “Trig Pos” (Trigger Position). With the left/right keys, you offset the trigger position in steps of 1 horizontal div. When using this technique, you can pan left/right to view the full sampling buffer (more than 13 full screens). When panning left/right, pressing B will reset trigger point back to center. When at center, this key will alternately show/hide the trigger position axis. To stop capture, you can use either SING trigger mode or use NORM/AUTO in combination with the A key (R/S on V1).

Empty areas far left and far right, represent time before and after the acquisition period. The size of these areas will change between acquisition cycles subject to the position where the trigger was found. Irrespective of empty areas, acquired data will always span the full capacity of the sampling buffer.

Resizing and zooming

A captured (stopped) waveform can be resized (zoomed in/out) through altering V/Div and/or T/Div. V/Div will either stretch or compress a waveform in the vertical dimension whereas T/Div will allow you to stretch/compress a waveform in the horizontal dimension. This feature applies to data currently in the sampling buffer (static data). Once acquisitions are restarted (using the A key), new data will be sampled using the currently active V/Div and T/Div selections.

Use menu item YA and sub option “Vert Pos” to scroll a waveform vertically. The left/right keys will offset vertical position of the displayed waveform in steps of 1 vertical div. This feature can be used with acquisitions running (live data) or stopped (static data). Pressing B with “Vert Pos” selected, will reset vertical offset back to zero.

Note that sampling an input signal with a high gain (low V/Div selection) may lead to distorted waveforms (flattened top and/or bottom) and inaccurate measurements. This is the case when the input voltage level exceeds the min/max levels for the selected V/Div. The Nano will check for this condition and display the V/div selection with a red color as a voltage out of range warning. Color will revert to normal (white), when V/Div is increased and/or the input voltage drops to within min/max for the selected V/Div.

Buffer priority and sampling speed

Use menu OT and sub option “Buffer Pri” to switch between buffer priority modes equal and post. In equal priority mode, an even split is used for waveform data before and after the trigger point. In post priority mode, maximum buffer capacity will be used for data after the trigger.

Trigger position will default to the center of the display when using priority mode equal. In post priority mode, trigger position will default to the left side in order to fit more post trigger data on screen. Sub option “Trig Pos” (menu XA) can be used to further adjust trigger position.

Use sub option “Smpl Speed” to switch between normal and fast sampling mode. In fast sampling mode, sampling rate (Sa/s) is increased at the expense of reduced sampling depth. This mode will improve resolution and accuracy for time related measurements (frequency, duty cycle and pulse width) of lower frequency signals. Fast sampling mode can also be used to reduce time between measurement updates (increase refresh rate) and to detect high frequency components on low frequency waveforms.

The relationship between active T/Div, sampling mode and sampling rate is as outlined in the following table:

T/Div	Normal	Fast
1 us	1 MSa/s	1 MSa/s
2 us	1 MSa/s	1 MSa/s
5 us	1 MSa/s	1 MSa/s
10 us	1 MSa/s	1 MSa/s
20 us	1 MSa/s	1 MSa/s
50 us	500 kSa/s	1 MSa/s
100 us	250 kSa/s	1 MSa/s
200 us	125 kSa/s	1 MSa/s
500 us	50 kSa/s	500 kSa/s
1 ms	25 kSa/s	250 kSa/s
2 ms	12.5 kSa/s	125 kSa/s
5 ms	5 kSa/s	50 kSa/s
10 ms	2.5 kSa/s	25 kSa/s
20 ms	1.25 kSa/s	12.5 kSa/s
50 ms	500 Sa/s	5 kSa/s
100 ms	250 Sa/s	2.5 kSa/s
200 ms	125 Sa/s	1.25 kSa/s
500 ms	50 Sa/s	500 Sa/s
1 s	25 Sa/s	250 Sa/s
2 s	12.5 Sa/s	125 Sa/s
5 s	5 Sa/s	50 Sa/s
10 s	2.5 Sa/s	25 Sa/s

Sampling depth in V3 firmware is 4098 points for the primary channel and 1024 points for the reference channel. Samples loaded into the reference channel will be normalized to fit a minimum of one full screen centered on the trigger point.

Acquisition display modes

Use menu OT and sub option “Disp Mode” to switch between average and peak display mode. This mode determines how the input waveform amplitude will be displayed for oversampled signals.

Peak mode will identify the minimum and maximum values in your input signal and use these when displaying the waveform. This can be useful when looking for higher frequency components (such as noise or narrow pulses) present in your input signal. Noise will appear more dominant in this mode.

Average can be used to reduce random noise from a displayed waveform. This may be preferred when the larger dominant waveform (such as a logic square wave) is your target of interest. Note that narrow pulses may appear with significantly reduced amplitude in this mode.

Exported XML data is not affected by this setting.

Profiles and power on defaults

Preferences can be saved to a micro-SD card for recall or to flash memory to act as power on defaults. First, use the various menu options to configure DSO Nano any way you prefer. Then choose menu FI and sub-option "Save Pro". Choose profile <S Flash> (using left/right keys) and press the B key (a confirmation will be displayed in the information field when save is complete). This will save all active settings to DSO internal flash memory for use as power on defaults. Profiles with a sequential number (e.g. S 001.CFG) will be saved to your SD card.

Select sub-option "Load Pro", choose a profile (using left/right keys) and press the B key to load from flash memory or SD card. Choose profile <L Factory> and press the B key to reset the Nano to factory defaults. This will reset active preferences and gain calibration to default values. Use save to flash (sub options "S Flash" and "Save Cal") to use these values as power on defaults.

Measurements

The following is a list of the measurements you can obtain directly from your Nano:

Name	AC/DC	Description
Freq	AC	Input frequency measured in Hz
Duty	AC	Duty cycle (high or low ratio) relative to Vavg
Vrms	AC	Root-mean-square voltage relative to Vavg
Pcnt	AC	Pulse count (count of high or low pulses)
Pwdt	AC	Pulse width (average duration of high or low pulses)
Vpp	AC+DC	Voltage difference (peak-to-peak) between Vmax and Vmin
Vmin	AC+DC	The minimum input voltage relative to ground
Vmax	AC+DC	The maximum (peak) input voltage relative to ground
Vavg	AC+DC	Average voltage (DC voltage)

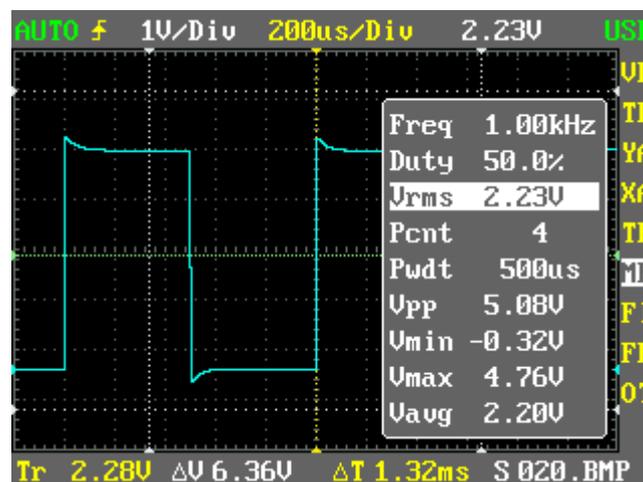
Measurement calculations start with identifying the AC part of the input signal. If at least one full cycle is detected, calculations will be restricted to the AC part of the waveform (data between the first and last opposing edge). That is, partial cycles at the beginning and end of the acquired waveform will be omitted from AC calculations. For signals with multiple cycles, calculations will be averaged across all cycles throughout the full acquisition buffer.

If no cycles are detected, calculations will be from all points inclusive, but limited to DC measurements.

Pulse width (**Pwdt**) is the calculated average duration of high or low pulses within the waveform. Use the rising edge trigger to measure high going pulses and falling edge trigger for low going pulses. Time is measured between two successive trigger level crossings.

Duty cycle is calculated as the ratio of high to full cycle when using rising edge trigger and low to full when using falling edge trigger.

Below is an example screen image of a 1.00 kHz square wave input signal with its associated measurements:



The highlighted/selected measurement (**Vrms**) is duplicated on the top bar for reference when the popup is closed.

Select menu ME and press the B key to save a screen capture to your micro-SD card with overlaid measurements.

Frequency Generator

The signal generator will output a square wave that can be used for test purposes (refer to the section on “DSO Nano Operation” for information on where the test signal output connector is located on your Nano). Output swing is from ground to the internal DSO lithium battery level. The output signal will peak (logic high level) at just above 3V for a near empty battery to 4.3V for a fully charged or charging battery. Peak-to-peak voltage (**V_{pp}**) may rise slightly above battery level due to a small undershoot (falling edge) and overshoot (rising edge) on the output square wave. Output level amplitude can not be altered.

Signal generator output frequency and duty cycle can be controlled as follows:

Output frequency can be set to three digits of precision in the range from 10Hz to 1MHz using menu FR and sub option “Freq Out”. Press the B key to cycle between 1, 2 and 3 digits of precision. Press left or right to alter the highlighted digit.

Duty cycle (pulse width modulation) can be set with sub option “Freq Duty” in steps of 1% (using left or right keys) from fully off to fully on. Press the B key to reset duty cycle back to the default 50%.

Calibration

Ground level calibration is automatically handled by the firmware and requires no manual intervention. Gain can be calibrated for each of the DSO Nano’s 6 hardware input ranges as follows:

Range	Probe	V/Div from to scale				Max voltage	
Range 1	X1	10	mV	100	mV	800	mV
Range 2	X1	200	mV	1	V	8	V
Range 3	X1	2	V	10	V	80	V
Range 4	X10	0.2	V	1	V	8	V
Range 5	X10	2	V	10	V	80	V
Range 6	X10	20	V	100	V	800	V

First step is to configure the DSO Nano for voltage measurement. Select trigger mode AUTO, T/Div 100us and **V_{avg}** as active measurement. Then choose a V/Div from the range you want to calibrate. Connect the probe to a known DC voltage reference and select sub option “Cal Gain” to start calibration. Then use left/right arrow to adjust gain until you have a **V_{avg}** reading that match your reference. Calibration data is automatically applied to all V/Div’s within the same gain range. Repeat the steps for a V/Div within each range to cover all 6 ranges.

Gain is applied as a percentage of full scale (see max voltage above). Pressing the B key with sub option “Cal Gain” selected will reset calibration data to factory defaults across V/Div’s in the same gain range.

Select sub option “Save Cal” and press B to save calibration data to FLASH (a confirmation will be displayed in the information field once data has been saved). Calibration data saved to FLASH will automatically be restored when you power on your Nano.

Files on SD cards

Configuration profiles (preferences), screen capture bitmaps and copies of the full DSO sampling buffer can be saved to files on micro-SD cards. Profiles and sampling buffer files can be read back. The files are laid out on the card as follows:

Directory	File	Content
IMAGE	IMAGExxx.BMP	Screen capture (write only)
PROFILE	FILExxx.CFG	Configuration files (read and write)
BUFFER	FILExxx.XML	Sampling buffer export files (read and write)

The x characters represent sequential numbers in the range 001 to 999 within each category.

When powering on the Nano, naming of new files will start with the first available number (highest file number on the card plus one) within each category. If you select and then write to an existing file, the file will be overwritten without warning. A successful write is followed by an automatic file sequence number increment.

When using left/right keys to select a save to file name, existing files will display with a red color. When selecting a load from file name, choice of name is limited to existing files.

In order to read files back, they must be placed in their designated directory with the proper file extension. It is possible however to change the base name of files from a PC when the DSO is connected via USB (e.g.FILE0001.CFG could be renamed to IGNITION.CFG). When selecting files to load, they will be listed in alphabetical order. Even though your PC’s operating system may support long filenames, DSO Nano will only display 8 uppercase characters for the base name.

Writing of files to micro-SD cards is immediate (whatever is displayed when activating write) except for XML files. Writes to XML files will be pending until the active acquisition cycle is complete. When in NORM or SING mode, this implies waiting for a successful trigger and subsequent post-fetch. You can also use the A key (R/S on V1) to stop acquisitions prior to saving. This allows full control of what gets written to the XML file. In SCAN mode however, writes will be immediate also for XML files, but limited to data between the leftmost point displayed and the current insertion point (just before the moving gap). Acquisitions will continue to run in real-time and the display will catch up once the write is complete.

Data points in XML files (export using sub option “Save Pri”) represent raw unconstrained data from the DSO Nano sampling buffer with 4 digits of precision.

XML data files can be loaded back into the primary channel (“Load Pri”) for later examination and measurements or to the reference channel (“Load Ref”). Sub option “Ref Pos” from the XA menu, can be used to vertically offset the reference waveform from the primary waveform.

Voltage range and sensitivity

Through use of the V/Div setting, we can configure the Nano to measure voltage levels in the range from 10mV/Div to 10V/Div with an x1 probe and 0.2V/Div to 100V/Div with an x10 probe. Note that the higher voltage range supported with x10 attenuation is a property of the probe, not of the Nano. That is, the x10 probe will reduce the voltage input to the Nano with a factor of 10 and thus protect it from excessive levels. Choice of attenuation (x1 or x10) should always match that of the probe.

Absolute limits for voltages that can be measured are as follows:

Probe	V/Div from to scale		Sensitivity		Max differential voltage (see text)		DC Input Resistance			
X1	10	mV	100	mV	288	uV	800	mV	1.02	MΩ
X1	200	mV	1	V	2.2	mV	8	V	546	kΩ
X1	2	V	10	V	23	mV	80	V	513	kΩ
X10	0.2	V	1	V	2.8	mV	8	V	1.02	MΩ
X10	2	V	10	V	22	mV	80	V	575	kΩ
X10	20	V	100	V	205	mV	800	V	517	kΩ

Sensitivity is the absolute minimum change in voltage that can be detected with the associated range of V/Div's.

Max input voltage is subject to choice of V/Div and ground position on the Nano display. With ground positioned at vertical center (use menu YA and sub option "Gnd Pos"), max range with an x1 probe and 10V/Div is from minus 40V to plus 40V. If we move ground position down, positive max voltage extends towards range max (see above table) while min voltage gets reduced towards zero. Moving ground position upwards will reverse the ratio of min to max levels. Exposure to voltages outside these limits may damage your Nano.

When excessive voltage levels are detected, the V/Div info field will be displayed with a red color. Start new measurements with a high V/Div, trigger mode AUTO and observe the color of the V/Div info field when connecting test leads. Disconnect the leads if the field turns red and/or increase V/Div to a safe level. Note that excessive levels will be reported for triggered data only. Test leads should always remain disconnected whenever the Nano is powered off.

DC input resistance is calculated from the Nano V1 and V2 datasheet's. Probe resistance is not accounted for in the specifications (a passive x10 probe should add a 9MΩ resistor in series with the Nano input).

Installation

The procedure to upgrade firmware is described in the manual that came with your DSO Nano. A copy of this manual (PDF file) can also be downloaded from the Seeed Studio product pages. You need to follow the steps in this procedure carefully and upload both the **DSO BenF APP v3.xx.dfu** and **DSO BenF LIB v3.xx.dfu** files. The order of upload (LIB or APP) is not significant.

Micro-SD cards must be formatted to use either the FAT16 or the FAT32 file system (NTFS and exFAT are not supported). The newer model high capacity SD cards (SDHC) are not supported. SD cards must support the SPI access protocol. The 2GB SanDisk card supplied by Seeed Studio has been confirmed to work well with the new V3 firmware. The FAT16 file system appears to be more responsive on Windows XP (e.g. when doing a directory refresh from the PC after writing a new image file to the card). This may or may not be the case on other platforms.

SD cards that have previously been formatted with the original Seeed Studio firmware must be reformatted prior to use. A utility program called “sdformatter” (Google for a download site) can be used to fully initialize a card to a known compatible format (sdformatter V2.9.0.5 was used for testing during development).

XML export files

Below is a condensed copy of an exported XML file showing 5 sample points around the trigger position. The **Profile** section includes information items documenting the active configuration at the time of export. There are also three numeric items in this section, namely **triggerIndex**, **sampleCount** and **timeRange**. The **sampleCount** item is the total number of sample points included in the file (4098 in the V3 firmware), **timeRange** is the time interval in seconds between the first (0) and last (4097) sample, **triggerIndex** is the index of the trigger sample point. Time between individual samples can be calculated as **timeRange** / **sampleCount**.

```
<?xml version="1.0" encoding="UTF-8"?>
<Document>
<Profile>
  <triggerMode>NORM</triggerMode>
  <triggerKind>EdgeRising</triggerKind>
  <triggerLevel>3.76V</triggerLevel>
  <triggerSensitivity>200mV</triggerSensitivity>
  <attenuation>x1</attenuation>
  <voltageDiv>1V</voltageDiv>
  <timeDiv>200us</timeDiv>
  <sampleDiv>200us</sampleDiv>
  <firmware>V3.40</firmware>
  <fileNumber>S003</fileNumber>
  <triggerIndex>1420</triggerIndex>
  <sampleCount>4098</sampleCount>
  <timeRange>32.784e-3</timeRange>
</Profile>
<Point>
  <seq>1418</seq>
  <val>-40.000e-3</val>
</Point>
<Point>
  <seq>1419</seq>
  <val>-40.000e-3</val>
</Point>
<Point>
  <seq>1420</seq>
  <val>5.280</val>
</Point>
<Point>
  <seq>1421</seq>
  <val>5.200</val>
</Point>
<Point>
  <seq>1422</seq>
  <val>5.160</val>
</Point>
</Document>
```

Each individual sample point is placed in a **Point** section. The **seq** item is the sequential number of the sample point in the range from 0 (first point in time) to **sampleCount** – 1, **val** is the measured voltage of the sample point.